

# LiNbO<sub>3</sub> Optical Waveguide Fabrication by High-Temperature Proton Exchange

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**Abstract**—An efficient method, the high-temperature proton exchange (HTPE), to fabricate high-quality LiNbO<sub>3</sub> optical waveguides is studied. The new proton exchange source, the stearic acid diluted by lithium stearate, is proposed for HTPE process. The known soft proton exchange (SPE) process can be realized by HTPE. There are no phase transitions when the  $\alpha$ -phase waveguides are fabricated by SPE. This phase presents the same crystalline structure as that of LiNbO<sub>3</sub> and, as expected, maintains the excellent nonlinear and electrooptical properties of the bulk material. The kinetics of HTPE is studied.

**Index Terms**—LiNbO<sub>3</sub>, optical waveguides, proton exchange.

## I. INTRODUCTION

LITHIUM niobate (LiNbO<sub>3</sub>) is a very important integrated optical material owing to its electrooptical and nonlinear optical properties. One of the basic methods to make optical waveguides in this crystal is proton exchange (PE). The use of proton exchange was started from work of Jackel *et al.* [1]. They described and fabricated optical waveguides in LiNbO<sub>3</sub> by PE in benzoic acid melt at 200–250 °C. The step-like index profiles with a surface refractive index increase of 0.12 for extraordinary polarization have been observed. Since then a lot of organic and inorganic melts used as a source of proton exchange were reported [2].

Despite the simplicity of the proton exchange technique, the PE LiNbO<sub>3</sub> waveguides exhibit very complex structural chemistry. Our work [2]–[5] has allowed us to identify seven different crystallographic phases H<sub>x</sub>Li<sub>1-x</sub>NbO<sub>3</sub> which can be realized in the PE LiNbO<sub>3</sub> waveguides. There is a phase jump when gradually varying the proton concentration in the exchange layer. This causes a sudden variation of the cell parameters, even if the crystallographic system is conserved. The most interesting for waveguide fabrication is that most of these discontinuities and phase jumps can already be seen on a rather simple diagram, which we called the *structural phase diagram*, where the surface index increase  $\Delta n_e$  is plotted as a function of the strain normal to the substrate surface,  $\varepsilon''_{33}$ . The  $\beta_i$  and  $\alpha$  phases can be fabricated by direct proton exchange or by annealing of

H<sub>x</sub>Li<sub>1-x</sub>NbO<sub>3</sub> phase with higher proton concentration, as following:  $\beta_4 \rightarrow \beta_3 \rightarrow \beta_2 \rightarrow \beta_1 \rightarrow \alpha$ . The  $\kappa_i$  phases cannot be formed by direct PE and are fabricated by postexchange annealing of the  $\beta_i$  phases only. Annealing is an important parameter in the fabrication of PE waveguides. Actually, most of the published results were obtained using heavily annealed PE waveguides (APE [6]), whose index profiles indicate that they are in the  $\alpha$ -phase. However, APE process, as was reported recently [7]–[11], can reduce the nonlinear coefficients or even destroy the periodic domain orientation in a portion of the waveguiding structure.

The  $\alpha$ -phase waveguides can also be created using a direct proton exchange process without postexchange annealing in a highly diluted melt of benzoic acid which has been called recently as soft proton exchange (SPE) [12]. The use of proton exchange in dilute benzoic acid has been proposed for the first time in [13]. SPE method gives rise to an exchanged layer in the  $\alpha$ -phase of better quality than the more popular APE method. The main reason for this is that SPE indicates no phase transitions. This allows preserving both the nonlinear coefficient and the domain orientation while fully benefiting from the power confinement associated with the guided wave configuration [8], [9]. Despite that the  $\alpha$ -phase waveguides prepared by APE and SPE methods have similar refractive indexes and strains. However, there is probably a principal difference in basic properties of the  $\alpha$ -phase waveguides prepared by these techniques. Indeed, El Hadi *et al.* [14] reported recently that the dispersion of extraordinary refractive-index increase in the  $\alpha$ -phase waveguides prepared by SPE method is high compared with that in the APE waveguides [15].

The known SPE processes were performed in benzoic acid diluted by lithium benzoate [8], [9], and [12]. The proton–lithium interdiffusion coefficient for the  $\alpha$ -phase is orders of magnitude smaller than that for the  $\beta_i$  phases [16], and one has to use very long processes to make the  $\alpha$ -phase single mode waveguides operating at 1.55  $\mu\text{m}$  wavelength (three days at 300 °C [12]). Therefore, it is important to increase the rate of the SPE process. This process rate can be increased by increasing the exchange temperature, however, the low boiling point of benzoic acid (249 °C [17]) and its high vapor pressure limit the temperature that can be used for SPE. What would be more convenient is a source with a higher boiling point and lower vapor pressure. Possible candidates include stearic (boiling point 374 °C [17]), oleic (369 °C), palmetic (360 °C), adipic (338 °C), and cinnamic (300 °C) acids [17]. Fig. 1 shows the dependences of vapor pressure on temperature for these acids [18]. One can see that widely used benzoic acid has the highest vapor pressure and

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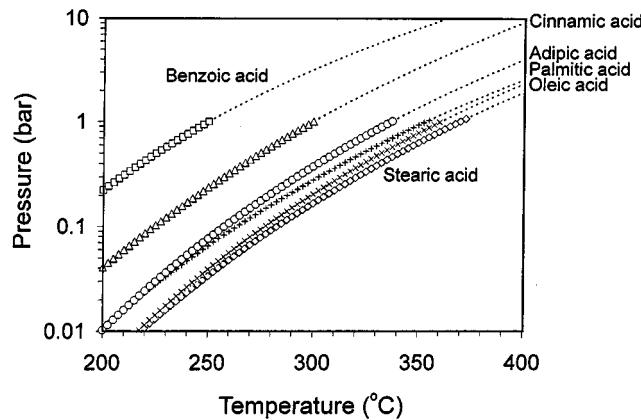


Fig. 1. Plot of vapor pressure versus temperature for some organic acids used as sources of PE [18].

therefore is most inconvenient for high temperature processing. In this study we used stearic acid, the acid with the highest boiling point (374 °C [17]) and lowest vapor pressure (Fig. 1, [18]) to fabricate LiNbO<sub>3</sub> optical waveguides by high-temperature proton exchange (HTPE).

As an alternative, so-called graded proton exchange (GPE) [19] could be also used for HTPE in a sulphate mixture with a relatively low acidity. This can be realized by adding small amount of hydrogen containing salt. However, the relatively high melting temperature for the sulphate mixture makes it inconvenient to use for practical waveguide designs.

In this paper we present the results of fabrication and characterization of LiNbO<sub>3</sub> optical waveguides prepared by HTPE process with a new proton exchange source, the mixture of stearic acid and lithium stearate. The pure stearic acid has been used in reports [20]–[25] as a proton source for fabrication of optical waveguides at temperatures from 220 to 270 °C. This acid is nontoxic, noncorrosive and is safe to use. In this paper we focus on high-temperature proton exchange (PE at temperatures higher than 300 °C), as a perspective method of deep  $\alpha$ -phase waveguide fabrication.

## II. SAMPLE PREPARATION AND CHARACTERIZATION

PE waveguides were fabricated in integrated optical grade virgin X-cuts LiNbO<sub>3</sub> substrates supplied by Crystal Technology, Inc. Despite the high boiling point of stearic acid the melt must be sealed, since the melt composition would otherwise change during exchange, due to differential evaporation of the melt constituents. The container design used is shown in Fig. 2. Before exchange the mixture of stearic acid and lithium stearate was melted to become homogeneous.

At temperatures higher than 400 °C the stearic acid is decomposed during the exchange process even when a hermetic container is used. Therefore, to study PE processes at temperatures above 400 °C, a eutectic mixture of sulphate salts with a small amount of KHSO<sub>4</sub> added was used as the proton exchange source [19]. The melt consisted of ZnSO<sub>4</sub> (41.1 mol.%), K<sub>2</sub>SO<sub>4</sub> (32.9 mol.%), Na<sub>2</sub>SO<sub>4</sub> (25.9 mol.%) and KHSO<sub>4</sub> added with concentrations from 0.01 to 0.2 mole per kg of this eutectic. The melting point of this mixture was 384 °C [26].

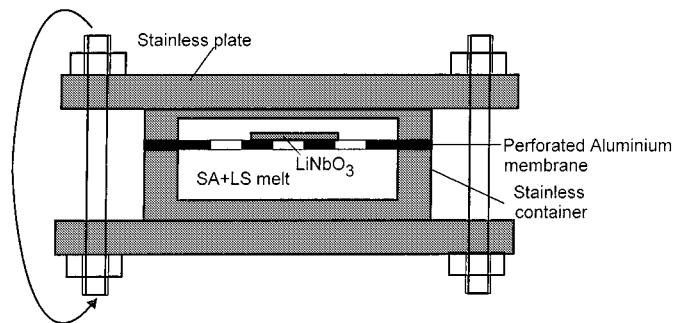


Fig. 2. Container used during HTPE process.

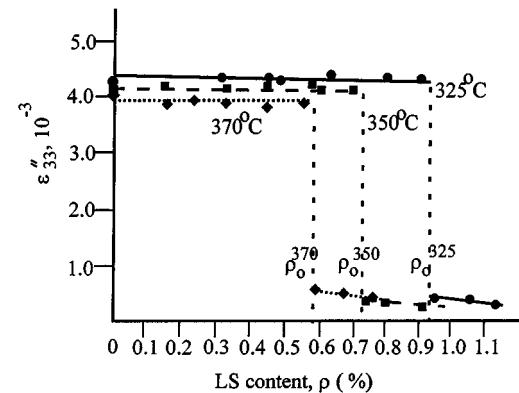


Fig. 3. Surface value of strain,  $\varepsilon''_{33}$ , versus composition of melt,  $\rho$ .

The depth index profiles of the uniform (single phase) waveguides were reconstructed by the IWKB technique proposed by White and Heidrich [27] and improved by Dikaev *et al.* [28]. All the fabricated waveguides were multimode at the 633 nm wavelength used throughout our studies. Therefore, we could determine the effective indexes of guided modes that are necessary for the IWKB technique by measuring the excitation angles of dark  $m$ -lines with a one-prism coupler setup. The effective indexes ranged from 2.21 to 2.30. The procedure for obtaining refractive index profiles for two-layer waveguides will be discussed in Section III.

For X-ray characterization, the strained state in the proton-exchanged layers was determined by analyzing the rocking curves obtained by a double-crystal X-ray diffractometer DRON-3 (Cu K $\alpha_1$  radiation) in accordance with the method developed in our previous work [29].

## III. EXPERIMENTAL RESULTS AND DISCUSSION

The melt used is characterized by the mass ratio of lithium stearate (LS) and stearic acid (SA):  $\rho = (m_{LS}/(m_{SL} + m_{SA})) \cdot 100\%$ . Varying  $\rho$  between 0–1% strongly modifies the phase of the exchanged layer. The surface value of strain,  $\varepsilon''_{33}$ , has been found to be independent of the exchange time.

Fig. 3 shows the variation of the H<sub>x</sub>Li<sub>1-x</sub>NbO<sub>3</sub> surface value of strain,  $\varepsilon''_{33}$ , as a function of the LS content and temperature of the melt. Two regions can be clearly recognized. For the PE in the melts with values of  $\rho$  lower than the threshold  $\rho_o$ , the exchanged structure is then stratified in two phase layers presenting two different indexes and strains. This has been verified

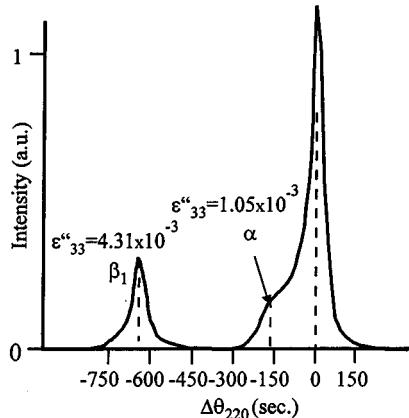


Fig. 4. X-ray rocking curve for (220) reflection from HTPC LiNbO<sub>3</sub> sample prepared on X-cut lithium niobate under following conditions:  $\rho = 0.4\%$ ,  $T = 350^\circ\text{C}$ ,  $t = 8\text{ h}$ .

by slowly removing the surface layer by successive polishing. The rocking curves show two different peaks, corresponding to the  $\beta_1$  and  $\alpha$ -phases (Fig. 4). The surface value of strains (highest value for the  $\beta_1$ -phase) is found to be largely independent of melt dilution for compositions up to threshold  $\rho_o$  (Fig. 3). With  $\rho$  higher than threshold  $\rho_o$ , which has been determined with a precision of 0.02%, the uniform  $\alpha$ -phase waveguides are formed, which present graded index profiles with a maximum index increase  $\Delta n_\alpha^o = 0.02$ .

The situation with refractive index measurements for samples prepared under conditions  $\rho < \rho_o$  is more complicated. The effective indexes,  $n_m$ , of all the modes of planar multimode waveguides can be experimentally determined using the prism coupling technique. Then feeding these data into an Inverse WKB [27], [28] reconstruction program, allows one to calculate the refractive index profile. However, the IWKB method assumes a continuous refractive index profile, but, as has been mentioned above, the real waveguides fabricated by HTPC with  $\rho < \rho_o$  are two-layer and standard IWKB method cannot be applied in this case.

Here we describe an algorithm, based on the IWKB method, which has been used to obtain the refractive index profile of two-layer PE planar waveguide.

The peak on the X-ray rocking curve for the  $\beta_1$  phase is sharp (Fig. 4) and deformation profile in the  $\beta_1$ -phase can be considered as step-like. Therefore, one can assume that the refractive index in the  $\beta_1$  phase is characterized by a step-like function and the realized waveguide consists of two layers (Fig. 5). Note, that the refractive index gradient for the  $\alpha$ -phase region is very small (less than  $0.005\text{ }\mu\text{m}^{-1}$ ), and the  $\alpha$ -phase region can be considered as an uniform substrate with refractive index  $n_\alpha^o$  for the surface step-like waveguide. The dispersion equation for  $n_m > n_\alpha^o$  can be written as [30]

$$kh_\beta [n_\beta^2 - n_m^2]^{1/2} = (m - 1)\pi + \phi_a + \phi_s \quad (1)$$

where  $n_\beta$  and  $h_\beta$  are refractive index and thickness of the step-like  $\beta_1$ -phase waveguide, respectively;  $n_\alpha^o$  the highest refractive index value for the  $\alpha$ -phase,  $n_m$  is an effective index of the  $m$ th mode,  $m = 1, 2, \dots, N$ , where  $N$  is the number

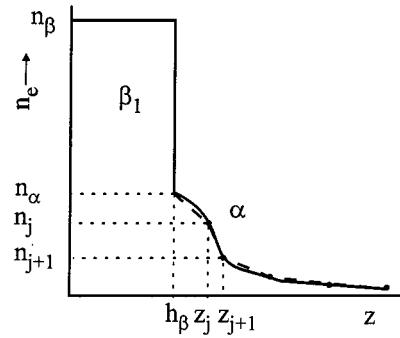


Fig. 5. Refractive index profile for the two-layer HTPC LiNbO<sub>3</sub> waveguide.

of modes in the waveguide. The  $k = 2\pi/\lambda_0$  is the free-space wavenumber with  $\lambda_0$  the free-space wavelength. The  $2\phi_a$  and  $2\phi_s$  are phase changes at the surface and substrate boundaries, respectively and are given by

$$2\phi_a = 2 \tan^{-1} \left\{ \xi \left[ \frac{n_m^2 - n_a^2}{n_\beta^2 - n_m^2} \right]^{1/2} \right\} \quad (2)$$

and

$$2\phi_s = 2 \tan^{-1} \left\{ \xi \left[ \frac{n_m^2 - (n_\alpha^o)^2}{n_\beta^2 - n_m^2} \right]^{1/2} \right\} \quad (3)$$

where  $n_a$  is the refractive index of the superstrate (it was air in our experiments, and  $n_a = 1$ ). The factor  $\xi$  discriminates between the transverse electric (TE) and transverse magnetic (TM) modes with  $\xi = 1$  for the TE modes and  $\xi = (n_\beta^2/n_{a,s}^2)$  for the TM modes.

The  $n_\alpha^o$  is known for a given temperature of PE, therefore by solving (1) with measured effective refractive indexes of, at least, two modes with  $n_m > n_\alpha^o$ , it is possible to obtain the refractive index  $n_\beta$  and thickness  $h_\beta$  of the  $\beta_1$ -phase region. The  $n_\beta$  is found to be largely independent of melt dilution for compositions up to threshold  $\rho_o$ . When  $n_\beta$  is known, by solving system (1) with measured effective refractive indexes of even one mode with  $n_m > n_\alpha^o$ , it is possible to obtain the thickness,  $h_\beta$ , of the thin  $\beta_1$ -phase region.

However, for  $n_m < n_\alpha^o$ , the situation is more complicated. For the monotonically decreasing graded-index waveguide, the eigenvalue equation can be written as [28]

$$k \int_0^{z_m} [n^2(z) - n_m^2]^{1/2} dz = (m - \frac{3}{4})\pi + \phi_a \quad m = 1, 2, \dots, N \quad (4)$$

where  $z_m$  is the turning point of the  $m$ th mode defined by  $n(z_m) = n_m$ . For the two-layer waveguide with step-like index profile for the  $\beta_1$ -phase and graded profile for the  $\alpha$ -phase (Fig. 5), (4) can be written as

$$kh_\beta [n_\beta(z) - n_m^2]^{1/2} + k \int_{h_\beta}^{z_m} [n^2(z) - n_m^2]^{1/2} dz = (m - \frac{3}{4})\pi + \phi_a. \quad (5)$$

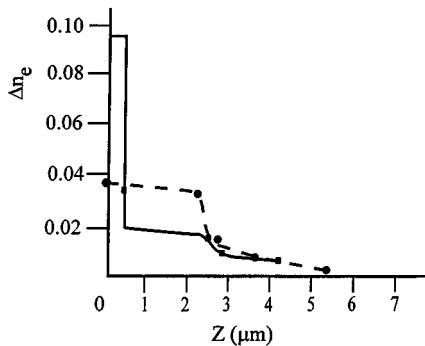


Fig. 6. Refractive profiles for HTPE LiNbO<sub>3</sub> waveguide fabricated under following conditions:  $\rho = 0.70\%$ ,  $T = 350\text{ }^\circ\text{C}$ ,  $t = 4.5\text{ h}$ . Dashed line: IWKB model. Solid line: Two-layer model.

According to White and Heidrich [27] with improvements made by Dikaev *et al.* [28], (5) is written as a sum of integrals

$$kh_\beta[n_\beta(z) - n_m^2]^{1/2} + k \sum_{j=0}^m \int_{z_j}^{z_{j+1}} [n^2(z) - n_m^2]^{1/2} dz = \left(m - \frac{3}{4}\right)\pi + \phi_a \quad (6)$$

where  $n_l = h_\beta$ , for all values of  $j$  with  $n_l > n_\alpha^o$ .

So as the values of  $n_\alpha^o$  and  $n_\beta$  are known, and assuming that  $n(z)$  is a piece-wise linear function connecting the measured values of  $n_m$  [27], i.e.

$$n(z) \approx n_j + \frac{(n_{j-1} - n_j)}{(z_j - z_{j-1})}(z_j - z) \quad \text{for } z_{j-1} \leq z \leq z_j \quad (7)$$

the turning points of the  $m$ -modes for the  $\alpha$ -phase region are determined.

Therefore, we have a simple algorithm for calculating  $h_\beta$  and  $z_m$  based only on previously determined values of  $n_\alpha^o$ ,  $n_\beta$  and  $n_m$ .

Fig. 6 shows the refractive index profiles calculated using the two-layer model (5) and with the usual IWKB model [27], [28]. One can see that without X-ray double crystal diffraction measurement, that makes sure that the real structure contains two layers, it is easy to be mistaken and assume that waveguide is in the  $\kappa_1$  phase [3]. However, the  $\kappa_1$  phase waveguides, formed by APE process, characterized by graded deformation profiles, and X-ray rocking curves show the graded variation of X-ray intensity with changing angle of diffraction around Bragg angle for (220) plane of LiNbO<sub>3</sub> [2], [3].

Fig. 7 shows the variation of the  $\text{H}_x\text{Li}_{1-x}\text{NbO}_3$  surface value refractive index increment,  $\Delta n_e$ , as a function of the LS content and temperature of the melt. Similar to Fig. 3, the two regions can be clearly recognized. The  $\Delta n_e$ , is found to be largely independent of melt composition for dilution up to threshold value,  $\rho_o$  (Fig. 7). As was shown above, the strain  $\varepsilon''_{33}$  is also independent of the content of LS in the melt up to threshold,  $\rho_o$  (Fig. 3). Therefore, the exchange ratio,  $x$  in  $\text{H}_x\text{Li}_{1-x}\text{NbO}_3$  is also constant for the fabrication regimes, when the  $\beta_1$ -phase is generated at the surface of waveguide (at  $\rho < \rho_o$ ). Fig. 8 shows the  $\varepsilon''_{33}$  and  $\Delta n_e$  as a function of the exchange temperature for the  $\beta_1$ -phase. One can see the monotonic decreasing of strains and index change with increasing temperature, which points to the  $\beta_1$  phase extending into the low concentration region with an

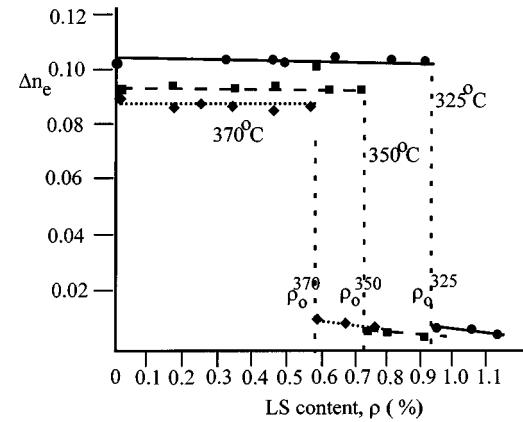


Fig. 7. Surface index change,  $\Delta n_e$ , versus composition to the melt,  $\rho$ , for different temperatures of HTPE.

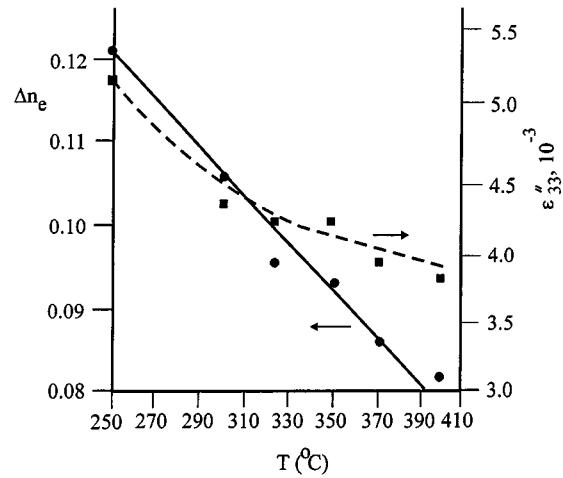


Fig. 8. Evolution of surface refractive index changes (dots) and strains (rectangles) for samples exchanged in pure stearic acid with increasing of exchange temperature.

increase in the exchange temperature. The index increment and deformations for the  $\alpha$ -phase are very small and the precision of their determination is not accurate enough to make any conclusions about the evolution of boundaries of the  $\alpha$ -phase with changing temperature.

The existence of jump on plot of  $\Delta n_e$  and  $\varepsilon''_{33}$  versus content of protons is not a specific feature of SA+LS melt and have been observed in other melts with the small hydrogen concentration. Fig. 9 shows that there are jumps on plots of  $\Delta n_e$  and  $\varepsilon''_{33}$  versus content of protons in the GPE melt even when the temperature of proton exchange is  $420\text{ }^\circ\text{C}$ . In the melts with the concentration of  $\text{KHSO}_4$  higher than threshold,  $C_H$ , the two-layer waveguides with the  $\beta_1$  phase at the surface and the  $\alpha$ -phase, as a bottom layer, are formed. With the concentration of  $\text{KHSO}_4$  lower than threshold  $C_H$ , the uniform  $\alpha$ -phase waveguides present a graded index profile with a maximum index increase  $\Delta n_\alpha^o = 0.02$ .

Our experiments confirm the earlier obtained results for low temperature PE [2]–[5], that neither the  $\kappa_1$  nor the  $\kappa_2$  phase can be formed by direct proton exchange.

Proton exchange diffusion is a process which follows the heterogeneous proton exchange reaction  $\text{H}^+ \rightarrow \text{Li}^+$  at the surface of LiNbO<sub>3</sub>. Both the refractive index and deformation profiles

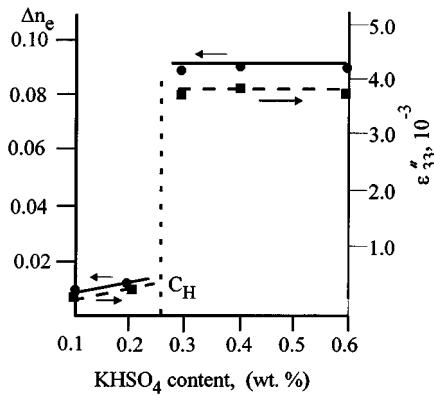


Fig. 9. Surface refractive index change (dots) and strains (rectangles) versus content of KHSO<sub>4</sub> in the melt ZnSO<sub>4</sub>-Na<sub>2</sub>SO<sub>4</sub>-K<sub>2</sub>SO<sub>4</sub>-KHSO<sub>4</sub> for waveguides fabricated by GPE method at the temperature of exchange  $T = 420^\circ\text{C}$ .

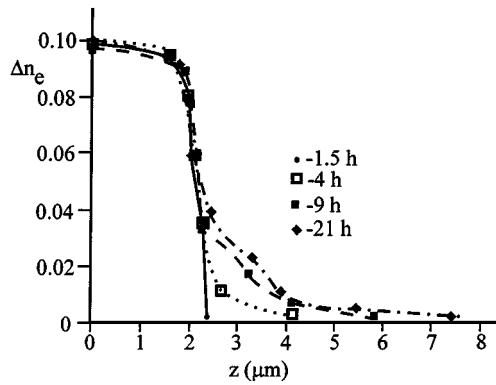


Fig. 10. Evolution of refractive index profile with increasing exchange time for waveguides fabricated by HTPE method in the melt of SA+SL with  $\rho = 0.50\%$  at  $T = 350^\circ\text{C}$ .

for the  $\beta_1$  region are step-like, and therefore similar to low temperature PE, and so one can expect that the hydrogen concentration profiles are step-like also. The depth of the  $\beta_1$ -phase region in the usual PE process, according to a large number of reports [2], grows proportionally to square root of exchange time, and can be expressed as  $h_\beta = \sqrt{2D(T) \cdot t}$ , where  $D(T)$  is temperature-dependent effective diffusion coefficient and  $t$  is the duration of exchange. However, for two-phase structures, realized by HTPE, the situation was determined to be much more complicated. Fig. 10 shows the evolution of refractive index profiles with increasing exchange time. One can see, that the thickness of the  $\beta_1$ -phase,  $h_\beta$ , is not changing during long periods of exchange time. Fig. 10 shows only four representative index profiles, but a large number of experiments has proved the validity of unusual kinetics of this process. However, the thickness of the  $\alpha$ -phase region is changing with exchange time. Therefore, flux of protons introduced in LiNbO<sub>3</sub> by heterogeneous H<sup>+</sup> → Li<sup>+</sup> exchange reaction is equal to flux of protons at the  $\beta_1/\alpha$ -phase boundary. Let us define the thickness of the  $\alpha$ -phase region as  $h_\alpha = z_N - h_\beta$ , where  $z_N$  is the turning point of last mode. Fig. 11 shows that  $h_\alpha$  grows proportionally to square root of exchange time. The explanation of the diffusion kinetics will be reported soon.

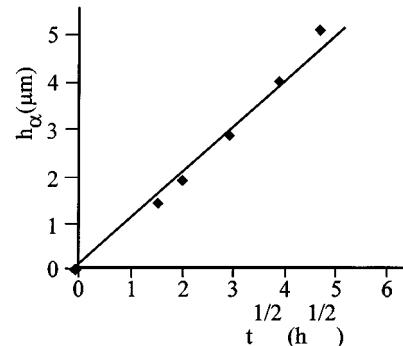


Fig. 11. The depth of the  $\alpha$ -phase,  $h_\alpha = z_N - h_\beta$ , as a function of exchange time  $t$  for the two-layer waveguides fabricated at  $T = 350^\circ\text{C}$  in the SA+SL melt with  $\rho = 0.50\%$ .

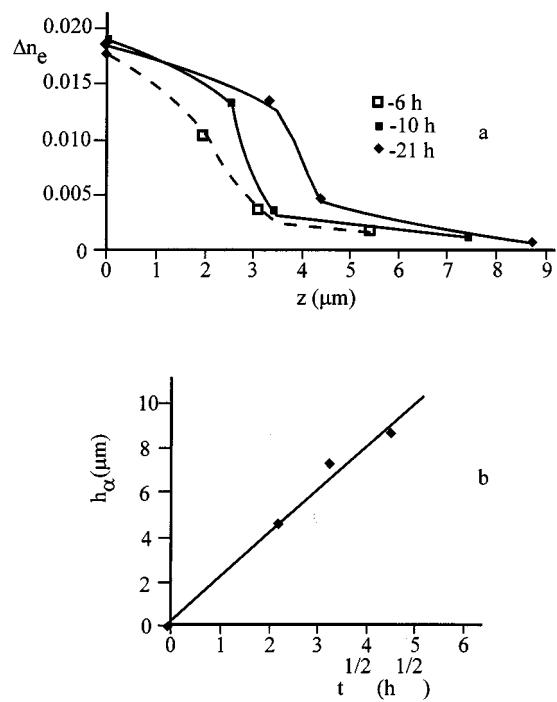


Fig. 12. Evolution of the  $\alpha$ -phase waveguide, prepared at  $350^\circ\text{C}$  in the SA+SL melt,  $\rho = 0.75\%$  with exchange time: (a) refractive index profiles and (b) depth versus square root of exchange time.

It has been found that for  $\rho > \rho_o$ , when the uniform  $\alpha$ -phase waveguides are formed [Fig. 12(a)], the thickness of the waveguide, defined as a turning point of the last mode, grows proportionally to the square root of the exchange time [Fig. 12(b)].

The uniform  $\alpha$ -phase channel waveguides were fabricated by HTPE. Fabrication of single mode channel waveguides was carried out by lift-off photolithographic technique to produce a series of 4-μm (for 850-nm wavelength) and 6-μm (for  $\lambda = 1550$ -nm) wide stripes on the sample surface. The pattern was formed by a 50-nm layer of SiO<sub>2</sub>. The propagation loss measured by edge coupling method was obtained to be less than 0.2 dB/cm. The 28-mm-long Y-splitters in LiNbO<sub>3</sub> were also fabricated by HTPE. By comparing input and total output power the insertion loss was estimated to be less than 5 dB, that points to good confinement of the  $\alpha$ -phase channel waveguides.

## IV. CONCLUSION

High temperature proton exchange in LiNbO<sub>3</sub> has been shown to be quite effective for producing high-quality  $\alpha$ -phase waveguides. The new proton exchange source, the stearic acid diluted by lithium stearate, has been proposed for HTPE. The parameters of HTPE process and properties of waveguides fabricated by this way are studied. The  $\alpha$ -phase waveguides can be fabricated by direct HTPE in a relatively short period time. There is not any phase transition when the  $\alpha$ -phase waveguides are fabricated by direct exchange. This phase presents the same crystalline structure as that of LiNbO<sub>3</sub> and, as expected, maintains the excellent nonlinear properties of the bulk material similar to SPE waveguides [8]–[12].

Finally, this possibility of producing high-quality waveguides with relatively short processing times opens the way for mass production of a large variety of integrated optical components.

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## REFERENCES

- J. L. Jackel, C. E. Rice, and J. J. Veselka, "Proton exchange for high-index waveguides in LiNbO<sub>3</sub>," *Appl. Phys. Lett.*, vol. 41, pp. 607–608, 1982.
- Y. N. Korkishko and V. A. Fedorov, *Ion Exchange in Single Crystals for Integrated Optics and Optoelectronics*. Cambridge, U.K.: Cambridge International Sci., 1999, pp. 97–269.
- , "Structural phase diagram of H<sub>x</sub>Li<sub>1-x</sub>NbO<sub>3</sub> waveguides: The correlation between structural and optical properties," *IEEE J. Select. Topics Quantum Electron.*, vol. 2, pp. 187–196, 1996.
- , "Relationship between refractive indices and hydrogen concentration in proton-exchanged LiNbO<sub>3</sub> waveguides," *J. Appl. Phys.*, vol. 82, pp. 171–183, 1997.
- Y. N. Korkishko, V. A. Fedorov, M. P. De Micheli, P. Baldi, K. El Hadi, and A. Leycuras, "Relationships between structural and optical properties of proton-exchanged waveguides on Z-cut lithium niobate," *Appl. Opt.*, vol. 35, pp. 7056–7060, 1996.
- P. G. Suchoski, T. K. Findakly, and F. J. Leonberger, "Stable low-loss proton-exchanged LiNbO<sub>3</sub> devices with no electro-optic degradation," *Opt. Lett.*, vol. 13, pp. 1050–1052, 1988.
- M. L. Bortz, L. A. Eyres, and M. M. Fejer, "Depth profiling of d<sub>33</sub> nonlinear coefficient in annealed proton exchanged LiNbO<sub>3</sub> waveguides," *Appl. Phys. Lett.*, vol. 62, pp. 2012–2014, 1993.
- K. El Hadi, M. Sundheimer, P. Aschieri, P. Baldi, M. P. De Micheli, D. B. Ostrowsky, and F. Laurell, "Quasiphase-matched parametric interactions in proton-exchanged lithium niobate waveguides," *J. Opt. Soc. Amer. B*, vol. 14, pp. 3197–3203, 1997.
- P. Baldi, M. P. De Micheli, K. El Hadi, S. Nouh, A. C. Cino, P. Aschieri, and D. B. Ostrowsky, "Proton exchanged waveguides in LiNbO<sub>3</sub> and LiTaO<sub>3</sub> for integrated lasers and nonlinear frequency converters," *Opt. Eng.*, vol. 37, pp. 1193–1202, 1998.
- Y. N. Korkishko, V. A. Fedorov, and F. Laurell, "Second order optical nonlinearity of different phases in proton exchanged LiNbO<sub>3</sub> waveguides," in *Proc. 9th European Conf. Integr. Opt. (ECIO'99)*, Turin, Italy, April 13–16, 1999, pp. 127–130.
- , "The nonlinear optical properties of different phases in proton exchanged lithium niobate waveguides," *IEEE J. Select. Topics Quantum Electron.*, vol. 6, Jan./Feb. 2000, to be published.
- L. Chanvillard, P. Aschieri, P. Baldi, M. De Micheli, D. B. Ostrowsky, L. Huang, and D. J. Bamford, "Highly efficient integrated optical parametric generator produced by soft proton exchange in PPLN," in *Proc. 9th European Conf. Integr. Opt. (ECIO'99)*, Turin, Italy, April 13–16, 1999, pp. 513–516.
- J. L. Jackel, C. E. Rice, and J. J. Veselka, "Composition control in proton LiNbO<sub>3</sub>," *Electron. Lett.*, vol. 19, pp. 387–388, 1983.
- K. El Hadi, V. Rastogi, M. R. Shenoy, K. Thyagarajan, M. De Micheli, and D. B. Ostrowsky, "Spectral measurement of the film-substrate index difference in proton-exchanged LiNbO<sub>3</sub> waveguides," *Appl. Opt.*, vol. 37, pp. 6463–6467, 1998.
- M. L. Bortz and M. M. Fejer, "Annealed proton-exchanged LiNbO<sub>3</sub> waveguides," *Opt. Lett.*, vol. 16, pp. 1844–1846, 1991.
- J. L. Jackel and C. E. Rice, "Short and long-term stability in proton exchanged lithium niobate waveguides," in *Proc. SPIE*, vol. 460, 1984, pp. 43–48.
- <http://webbook.nist.gov> (1998, Nov.) NIST Standard Reference Database Number 69 WebBook. Nat. Inst. Standards and Technol., Gaithersburg, MD, W. G. Mallard and P.J. Linstrom, Eds.
- D. R. Stull, "Vapor pressure of pure substances organic compounds," *Indust. Eng. Chem.*, vol. 39, pp. 517–540, 1947.
- V. A. Ganshin and Y. N. Korkishko, "Proton exchange in lithium niobate and lithium tantalate single crystals: Regularities and specific features," *Phys. Stat. Sol. (a)*, vol. 119, pp. 11–25, 1990.
- T. Maciak, "Stearic acid as a protonic source for fabrication of LiNbO<sub>3</sub> waveguides by proton exchange," *Optica Applicata*, vol. 20, pp. 209–211, 1990.
- V. A. Ganshin, Yu. N. Korkishko, T. V. Morozova, and V. V. Saraikin, "The study of proton exchange in lithium tantalate crystals," *Phys. Stat. Sol. (a)*, vol. 114, pp. 457–465, 1989.
- S. Zhao, E. Y. B. Pun, and P. S. Chung, "Annealing effects on proton-exchanged LiNbO<sub>3</sub> optical waveguides using stearic acid," *Microwave Optic. Technol. Lett.*, vol. 5, pp. 490–493, 1992.
- E. Y. Pun, K. K. Loi, S. Zhao, and P. S. Chung, "Annealing properties of proton-exchanged waveguides in LiNbO<sub>3</sub> fabricated using stearic acid," in *Proc. SPIE*, vol. 1583, 1991, pp. 102–108.
- , "Proton-exchanged LiNbO<sub>3</sub> optical waveguides using stearic acid," *IEEE Photon. Technol. Lett.*, vol. 3, pp. 1006–1008, 1991.
- S. Zhao, E. Y. B. Pun, and P. S. Chung, "Effect of annealing on proton-exchanged LiNbO<sub>3</sub> waveguides fabricated using stearic acid," *Chinese J. Lasers*, vol. 23, pp. 806–810, 1996.
- N. V. Khakhlova and N. S. Dombrovskaya, "Fusion of the sodium, potassium, and zinc sulphate ternary system," *Russian J. Inorgan. Chem.*, vol. 4, pp. 416–420, 1959.
- J. M. White and P. F. Heidrich, "Optical waveguide refractive index profiles determined from measurement of mode indices: A simple analysis," *Appl. Opt.*, vol. 15, pp. 151–155, 1976.
- Y. M. Dikaev, Yu. A. Kopylov, and I. M. Kotelyanskii, "Simple method to determine the index profiles in graded waveguides," *Kvantovaya Elektronika*, vol. 8, pp. 378–381, 1981.
- V. A. Fedorov, V. A. Ganshin, and Y. N. Korkishko, "New method of double-crystal X-ray diffractometric determination of the strained state in surface-layer structures," *Phys. Stat. Sol.(a)*, vol. 135, pp. 493–505, 1993.
- C. R. Pollock, *Fundamentals of Optoelectronics*. Boston, MA: Irwin, 1990, pp. 96–97.



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